

Search Notes

Application/Control No.

10/042,762

Examiner

Hanh Nguyen

Applicant(s)/Patent under
Reexamination

LI ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
375	240.11	8/21/2006	HN
	240.1		
	240.15		
	240.21		
	240.12		
	240.08		
375	240		
370	235		
	229		
	230		
	236		
370	238		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	8/21/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner